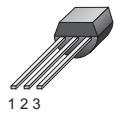


**HAOPIN MICROELECTRONICS CO.,LTD.**
**Description**

Glass passivated, sensitive gate thyristors in a plastic envelope, intended for use in general purpose switching and phase control applications. These devices are intended to be interfaced directly to microcontrollers, logic integrated circuits and other low power gate trigger circuits.

Symbol	Simplified outline
	 TO-92
Pin	Description
1	Cathode
2	anode
3	gate
TAB	anode

**Applications:**

- ◆ Motor control
- ◆ Industrial and domestic lighting
- ◆ Heating
- ◆ Static switching

**Features**

- ◆ Blocking voltage to 600 V
- ◆ On-state RMS current to 1.25 A
- ◆ Ultra low gate trigger current

SYMBOL	PARAMETER	Value	Unit
$V_{DRM}$	Repetitive peak off-state voltages	600	V
$I_T \text{ (RMS)}$	RMS on-state current (full sine wave)	1.25	A
$I_{TSM}$	Non-repetitive peak on-state current (full cycle, $T_j$ initial=25°C)	25	A

SYMBOL	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNIT
$R_{th j-l}$	Junction to leads		-	-	60	°C/W
$R_{th j-a}$	Junction to Ambient		-	-	150	°C/W



# X0202MA

## SCRs

HAOPIN MICROELECTRONICS CO.,LTD.

Limiting values in accordance with the Maximum system(IEC 134)

SYMBOL	PARAMETER	CONDITIONS	MIN	Value	UNIT
$V_{DRM}$	Repetitive peak off-state Voltages		-	600	V
$I_{T(RMS)}$	RMS on-state current (180° conduction angle)	$TJ=55^\circ C$	-	1.25	A
$I_{T(AV)}$	Average On-state current (180° conduction angle)	$TJ=55^\circ C$	-	0.8	A
$dI/dt$	Critical rate of rise of on-state current	$I_g=2 \cdot I_{GT}, \ tr \leq 100 \text{ ns} \quad F=60 \text{ Hz} \quad TJ=125^\circ C$	-	50	A/ $\mu$ s
$I_{TSM}$	Non repetitive surge peak on-state current	$tp=8.3 \text{ ms} \quad TJ=25^\circ C$	-	25	A
		$tp=10 \text{ ms} \quad TJ=25^\circ C$	-	22.5	A
$I^2t$	$I^2t$ Value for fusing	$tp=10 \text{ ms} \quad TJ=25^\circ C$	-	2.5	$\text{A}^2\text{s}$
$I_{GM}$	Peak gate current	$Tp=20 \mu \text{ s} \quad TJ=125^\circ C$	-	1.2	A
$P_{G(AV)}$	Average gate power dissipation	$TJ=125^\circ C$	-	0.2	W
$T_j$	Operating junction temperature range		-40	125	$^\circ C$
$T_{stg}$	Storage junction temperature range		-40	150	$^\circ C$

$T_j=25^\circ C$  unless otherwise stated

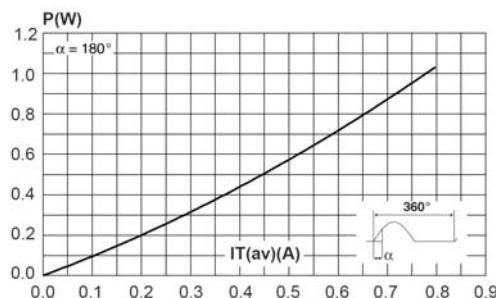
SYMBOL	TEST	CONDITIONS	MIN	TYP	MAX	UNIT
Static characteristics						
$I_{GT}$	$V_D=12V \ RL=140 \Omega$		-	-	200	$\mu A$
$V_{GT}$	$V_D=12V \ RL=140 \Omega$		-	-	0.8	V
$V_{GD}$	$V_D=V_{DRM} \ R_L=3.3 \text{ k}\Omega$ $R_{GK}=1 \text{ k}\Omega$	$Tj=125^\circ C$	0.1	-	-	V
$V_{RG}$	$I_{RG}=10 \mu A$		8	-	-	V
$I_L$	$I_G=1 \text{ mA} \ R_{GK}=1 \text{ k}\Omega$		-	-	6	mA
$I_{DRM}$ $I_{RRM}$	$V_D=V_{DRM} \ R_{GK}=1 \text{ k}\Omega$ $V_R=V_{RRM}$	$Tj=25^\circ C$ $Tj=125^\circ C$	-	-	5 500	$\mu A$
$I_H$	$I_T=50 \text{ mA} \ R_{GK}=1 \text{ k}\Omega$		-	-	5	mA
$V_{TM}$	$V_{TM}=2.5 \text{ A} \ tp=380 \ \mu \text{ s}$	$Tj=25^\circ C$	-	-	1.45	V

### Dynamic Characteristics

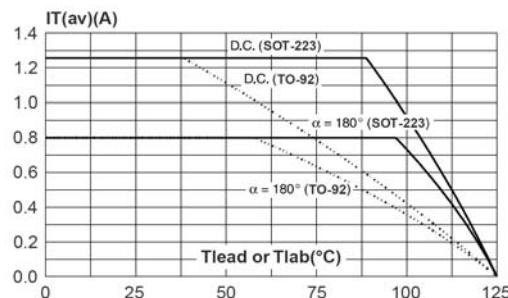
Dv/dt	$V_D=67\%V_{DRM} \ R_{GK}=1 \text{ k}\Omega$	$Tj=110^\circ C$	10	-	-	$V/\mu \text{ s}$
Vto	Threshold voltage	$Tj=125^\circ C$	-	-	0.9	V
Rd	Dynamic resistance	$Tj=125^\circ C$	-	-	200	$\text{m}\Omega$

**HAOPIN MICROELECTRONICS CO.,LTD.**
**Description**

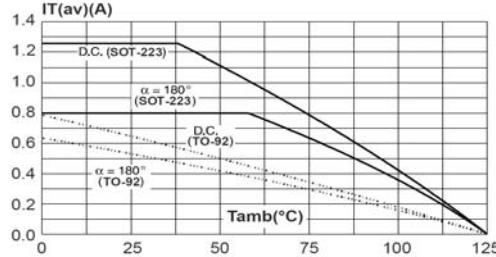
**Fig. 1:** Maximum average power dissipation versus average on-state current.



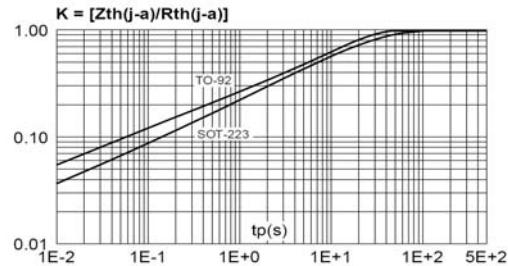
**Fig. 2-1:** Average and D.C. on-state current versus lead temperature (SOT-223/TO-92).



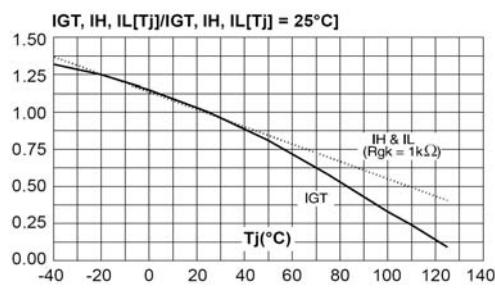
**Fig. 2-2:** Average and D.C. on-state current versus ambient temperature (device mounted on FR4 with recommended pad layout) (SOT-223/TO-92).



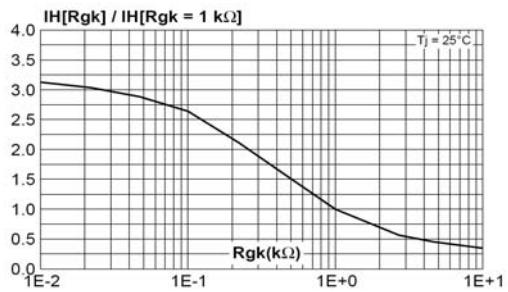
**Fig. 3:** Relative variation of thermal impedance junction to ambient versus pulse duration (SOT-223/TO-92).



**Fig. 4:** Relative variation of gate trigger current, holding current and latching current versus junction temperature (typical values).

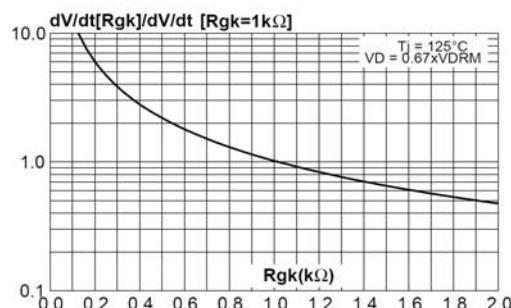


**Fig. 5:** Relative variation of holding current versus gate-cathode resistance (typical values).

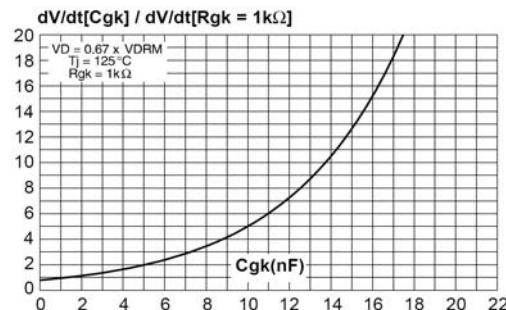


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**Description**

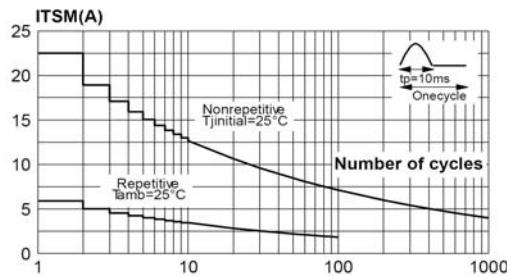
**Fig. 6:** Relative variation of  $dV/dt$  immunity versus gate-cathode resistance (typical values).



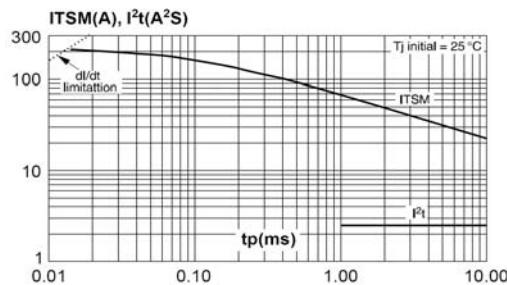
**Fig. 7:** Relative variation of  $dV/dt$  immunity versus gate-cathode capacitance (typical values).



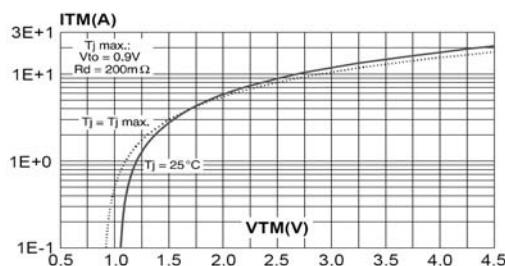
**Fig. 8:** Surge peak on-state current versus number of cycles.



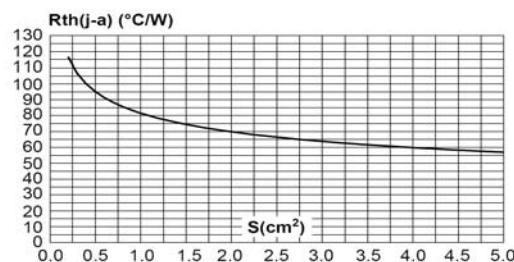
**Fig. 9:** Non-repetitive surge peak on-state current for a sinusoidal pulse with width  $tp < 10$  ms, and corresponding value of  $I^2t$ .



**Fig. 10:** On-state characteristics (maximum values).



**Fig. 11:** Thermal resistance junction to ambient versus copper surface under tab (Epoxy printed circuit board FR4, copper thickness: 35  $\mu$ m) (SOT-223).



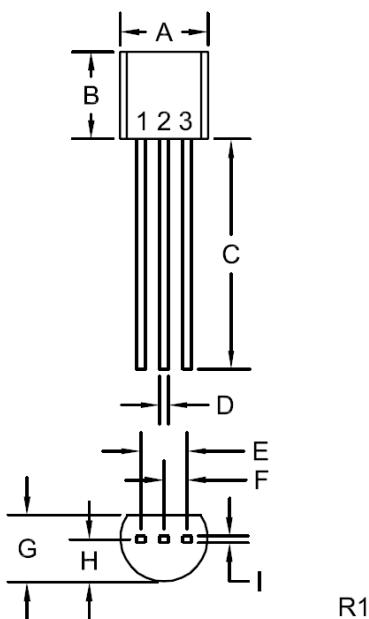
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## Description

Dimensions in mm

Net Mass: 0.2 g

TO-92



SYMBOL	DIMENSIONS			
	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A (DIA)	0.175	0.205	4.45	5.21
B	0.170	0.210	4.32	5.33
C	0.500	-	12.70	-
D	0.016	0.022	0.41	0.56
E	0.100		2.54	
F	0.050		1.27	
G	0.125	0.165	3.18	4.19
H	0.080	0.105	2.03	2.67
I	0.015		0.38	

TO-92 (REV: R1)

R1